Special Issue

Emerging Technologies in Information Security and Cryptography

Message from the Guest Editors

This Special Issue strives to address security challenges, i.e., new attack vectors and information security risks, introduced by cultural, technological, organizational, and policy changes. Solutions to these challenges include the development of new security and cryptographic approaches, the evaluation of information security awareness measures, the evolution of information security management systems and processes, and the study of regulations and standardization.

Guest Editors

Dr. Stephan Neumann

Dr. Jurlind Budurushi

Dr. Malika Bendechache

Deadline for manuscript submissions

closed (20 March 2024)



Applied Sciences

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mdpi.com/si/139935

Applied Sciences
Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
applisci@mdpi.com

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multidimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo

Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32, 20133 Milano, Italy

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